

Application specific true critical paths identification in sequential circuits

Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan; Devadze, Sergei; Oyeniran, Adeboye Stephen
2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 299-304 : ill <https://doi.org/10.1109/IOLTS.2019.8854442>

Efficient fault injection based on dynamic HDL slicing technique

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Raik, Jaan; Sauer, Christian 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 52-53 : ill
<https://doi.org/10.1109/IOLTS.2019.8854419>

PASCAL : timing SCA resistant design and verification flow

Lai, Xinhui; Jenihhin, Maksim; Raik, Jaan; Paul, Kolin 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 239-242 : ill <https://doi.org/10.1109/IOLTS.2019.8854458>